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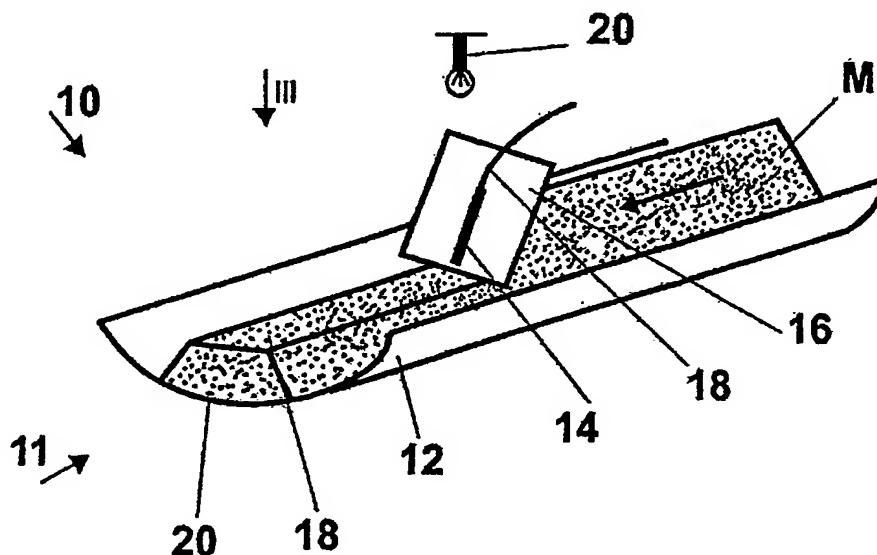
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(54) Title: SPECTRAL ANALYSIS APPARATUS FOR MEASURING INTERMEDIATE LAYERS OF MINERAL SAMPLERS



(57) Abstract: A method of spectral analysis of a mineral (M) in granular form is disclosed. The mineral (M) is moved through an illumination zone (18) and a beam of light is directed at the mineral (M) to illuminate it. Light reflected off the mineral (M) is collected and then spectrally analysed to obtain information pertaining to the composition of the granular material (M). The mineral (M) is in the form of a layer having an undersurface (20) and a top surface (22). The illumination zone (18) is intermediate the undersurface (20) and the top surface (22).

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